jc971 U.S. PTO
09/811435
03/20/01

| Subclass | ISSUE CLASSIFICATION |
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| Class | |

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PATENT NUMBER

# U.S. UTILITY Patent Application

| O.I.P.E. | PATENT DATE |
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| APPLICATION NO. | CONT/PRIOR | CLASS | SUBCLASS | ART UNIT | EXAMINER |
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| 09/811435 | F | 716/14 | 738 | 2825 2123 | Decady |

APPLICANTS

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TITLE

Test method of semiconductor intergrated circuit and test pattern generator

PTO-2040
12/99

## ISSUING CLASSIFICATION

| ORIGINAL | | CROSS REFERENCE(S) | |
|---|---|---|---|
| CLASS | SUBCLASS | CLASS | SUBCLASS (ONE SUBCLASS PER BLOCK) |
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INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

| ☐ TERMINAL DISCLAIMER | DRAWINGS | | | CLAIMS ALLOWED | |
|---|---|---|---|---|---|
| | Sheets Drwg. | Figs. Drwg. | Print Fig. | Total Claims | Print Claim for O.G. |
| ☐ The term of this patent subsequent to _____ (date) has been disclaimed. | | | | NOTICE OF ALLOWANCE MAILED | |
| ☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ | | | | ISSUE FEE | |
| | | | | Amount Due | Date Paid |
| ☐ The terminal ___months of this patent have been disclaimed. | | | | ISSUE BATCH NUMBER | |

(Assistant Examiner) (Date)

(Primary Examiner) (Date)

(Legal Instruments Examiner) (Date)

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